Search Notes

Application/Control No.

Applicant(s)/Patent under Reexamination

10/783,666

TOYOSHIMA, YOUHEI

Examiner

2837

Jeremy Luks

SEARCHED					
Class	Subclass	Date	Examiner		
181	249,255, 264,272, 251,257, 268	7/18/2006	JL		
	275				
			<u> </u>		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	<u> </u>				

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
See attached search notes	7/18/2006	JL
Consulted Edgardo San Martin, Primary Examiner, Class 181	7/18/2006	JL
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